



List of Patents and Publications for Information Disclosure Statement

Applicant(s): David L. Myers Docket 18079
 Serial No.: 10/748,893 Group: 1762
 Filed: December 30, 2003 Examiner: Marianne Padgett

U.S. PATENT DOCUMENTS							
Initials		Doc. No.	Date	Name	Class	Subclass	Filing Date
/MLP/	A1	3,692,618	9/19/1972	Dorschner et al.			
	A2	3,802,817	4/9/1974	Matsuki et al.			
	A3	3,849,241	11/19/1974	Butin et al.			
	A4	3,995,014	5/4/1976	Mostev et al.			
	A5	4,110,143	8/29/1978	Cogliano et al.			
	A6	4,145,378	3/20/1979	Arrighetti et al.			
	A7	4,340,563	7/20/1982	Appel et al.			
	A8	4,880,849	11/14/1989	Poole et al.			
	A9	5,108,820	4/28/1992	Kaneko et al.			
	A10	5,266,643	11/30/1993	Mustonen et al.			
	A11	5,272,236	12/21/1993	Lai et al.			
	A12	5,278,272	1/11/1994	Lai et al.			
	A13	5,332,613	7/26/1994	Taylor et al.			
	A14	5,336,552	8/9/1994	Strack et al.			
	A15	5,382,400	1/17/1995	Pike et al.			
	A16	5,411,994	5/2/1995	Galli et al.			
	A17	5,539,056	7/23/1996	Yang et al.			
	A18	5,596,052	1/21/1997	Resconi et al.			
	A19	5,652,281	7/29/1997	Galli et al.			
	A20	5,688,465	11/18/1997	Myers			
	A21	5,962,594	10/5/1999	Raetzsch et al.			
	A22	6,384,100	5/7/2002	Choi			
/MLP/	A23	6,414,048	7/2/2002	Sanduja et al.			

Foreign Patent Documents

						Trans.		
Initials		Doc. No.	Date	Country	Class	Subclass	Yes	No
/MLP/	A1	EP 0447239 B1	'6/12/1996	EP			✓	
	A2	EP 0601682 B1	1/28/1998	EP			✓	
	A3	EP 0673396 B1	7/8/1998	EP			✓	
	A4	EP 0725090 B1	6/7/2000	EP				✓
	A5	WO 01/17575	3/15/2001	WO-PCT			✓	
/MLP/	A6	WO 02/20658	3/14/2002	WO-PCT			✓	

Other Documents

Initials		Author, Title, Date, Pages, etc.
/MLP/	A1	ASTM Designation: D 724-89, "Standard Test Method for Surface Wettability of Paper (Angle-of-Contact Method), July 1989, pp. 113-115.

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/MLP/	A2	Patent Abstracts of Japan, JP 55016022A, 2/4/1980.
	A3	Patent Abstracts of Japan, JP 63210143A, 8/31/1988.
	A4	Patent Abstracts of Japan, JP 01011108A, 1/13/1989.
	A5	Abstract, JP 01016817A2, 1/20/1989.
	A6	Patent Abstracts of Japan, JP 02059029A, 2/28/1990.
	A7	Patent Abstracts of Japan, JP 02182714A, 7/17/1990.
	A8	Patent Abstracts of Japan, JP 03281544A, 12/12/1991.
	A9	Patent Abstracts of Japan, JP 06078401B4, 10/5/1994.
	A10	Patent Abstracts of Japan, JP 07090783A, 4/4/1995.
	A11	Patent Abstracts of Japan, JP 07145559A, 6/6/1995.
	A12	Patent Abstracts of Japan, JP 07278327A, 10/24/1995.
	A13	Patent Abstracts of Japan, JP 07324102A, 12/12/1995.
	A14	Patent Abstracts of Japan, JP 09176349A, 7/8/1997.
	A15	Patent Abstracts of Japan, JP 10034071A, 2/10/1998.
	A16	Patent Abstracts of Japan, JP 11120982A, 4/30/1999.
/MLP/	A17	Patent Abstracts of Japan, JP 2000355878A, 12/26/2000.

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609.
 Draw line through citation if not in conformance and not considered. Include a copy of this form with your next communication.

Examiner:

Date Considered:

/Marianne L. Padgett/

06/25/2007